

<b>Notice of References Cited</b>	Application/Control No. 10/772,439	Applicant(s)/Patent Under Reexamination GAIK, LEONARD J.	
	Examiner THUY-VI NGUYEN	Art Unit 3689	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0154759	10-2002	Ishii, Miruka	379/373.01
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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**FOREIGN PATENT DOCUMENTS**

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